

# **Notice of References Cited**

Application/Control No.

09/835,491

Applicant(s)/Patent Under  
Reexamination  
OZAWA ET AL.

Examiner

Thoi V Duong

Art Unit

2871

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## **U.S. PATENT DOCUMENTS**

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	B	US-5092664	03-1992	Miyatake et al.	359/41
	C	US-6339459 B1	01-2002	Ichikawa et al.	349/95
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## **NON-PATENT DOCUMENTS**

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	U	US 2002/0085154 A1, Hattori et al., July 04, 2002.
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